

April 2013

# FQA13N50CF

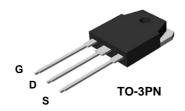
# N-Channel QFET® FRFET® MOSFET 500 V, 15 A, 48 m $\Omega$

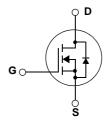
#### **Features**

- 15 A, 500 V,  $R_{DS(on)}$  = 48 m $\Omega$  (Max.) @  $V_{GS}$  = 10 V,  $I_D$  = 7.5 A
- Low Gate Charge (Typ. 43 nC)
- Low C<sub>rss</sub> (Typ. 20 pF)
- 100% Avalanche Tested
- Fast Recovery Body Diode (Typ. 100 ns)

## **Description**

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.





# **Absolute Maximum Ratings**

Symbol	Parameter		FQA13N50CF	Unit	
V <sub>DSS</sub>	Drain-Source Voltage		500	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		15	А	
	- Continuous (T <sub>C</sub> = 100°C)		9.5	Α	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	60	А	
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	860	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	15	А	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	21.8	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5	V/ns	
$P_{D}$	Power Dissipation (T <sub>C</sub> = 25°C)		218	W	
	- Derate above 25°C	1.56	W/°C		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to +150	°C		
TL	Maximum lead temperature for soldering purposes 1/8""from case for 5 seconds	300	°C		

#### **Thermal Characteristics**

Symbol	Parameter	FQA13N50CF	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.58	°C/W	
$R_{\theta JS}$	Thermal Resistance, Case-to-Sink, Typ.	0.24	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	40	°C/W	

# **Package Marking and Ordering Information**

<b>Device Marking</b>	Device	Package	Reel Size	Tape Width	Quantity
FQA13N50CF	FQA13N50CF	TO-3PN			30
FQA13N50CF	FQA13N50CF_F109	TO-3PN			30

# **Electrical Characteristics** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Charac	teristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	500			V
$\Delta BV_{DSS}/$ $\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°C		0.5		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V			1	μА
		V <sub>DS</sub> = 400 V, T <sub>C</sub> = 125°C			10	μА
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Charact	eristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 7.5A		0.43	0.48	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 7.5 A (Note 4)		15		S
Dynamic Cl	haracteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		1580	2055	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		180	235	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			20	25	pF
Switching C	Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 250 \text{ V}, I_D = 15\text{A},$		25	60	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		100	210	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	4145		130	270	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		100	210	ns
Qg	Total Gate Charge	$V_{DS} = 400 \text{ V}, I_{D} = 15\text{A},$		43	56	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		7.5		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		18.5		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings	3				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				15	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				60	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 15 A			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 15 \text{ A},$		100		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		0.4		μС

#### NOTES

<sup>1.</sup> Repetitive Rating : Pulse width limited by maximum junction temperature

<sup>2.</sup> L = 5.6mH, I  $_{AS}$  =15A, V  $_{DD}$  = 50V,  $R_{G}$  = 25  $\Omega,$  Starting  $\,$  T  $_{J}$  = 25°C  $\,$ 

<sup>3.</sup>  $I_{SD} \le 15 A$ , di/dt  $\le 200 A/\mu s$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25^{\circ}C$ 

<sup>4.</sup> Pulse Test : Pulse width  $\leq 300 \mu \text{s}, \, \text{Duty cycle} \leq 2\%$ 

<sup>5.</sup> Essentially independent of operating temperature

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

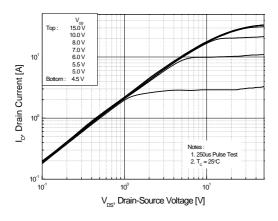
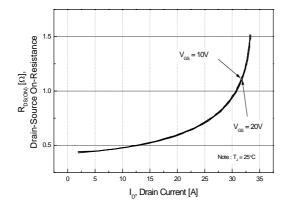
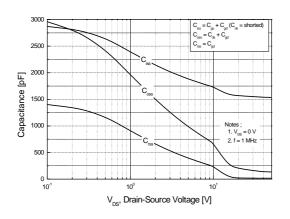


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage



**Figure 5. Capacitance Characteristics** 



**Figure 2. Transfer Characteristics** 

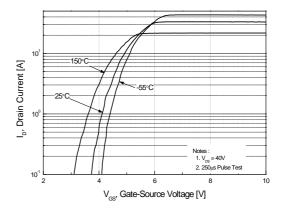


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

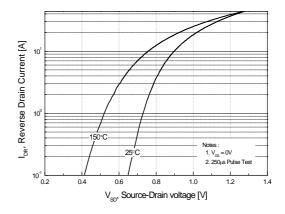
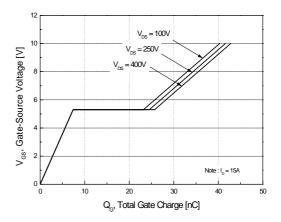


Figure 6. Gate Charge Characteristics



# Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

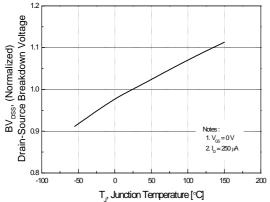


Figure 9. Maximum Safe Operating Area

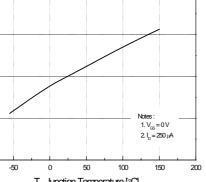


Figure 8. On-Resistance Variation vs. Temperature

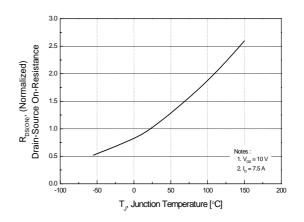


Figure 10. Maximum Drain Current vs. Case Temperature

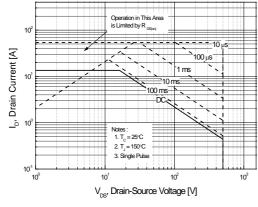
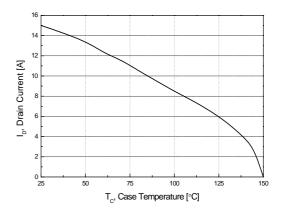
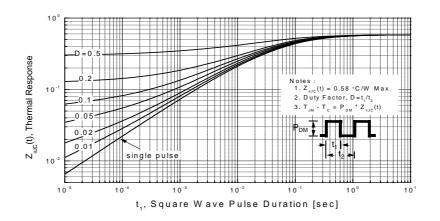
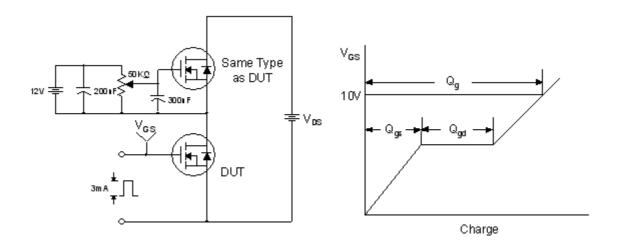


Figure 11. Transient Thermal Response Curve

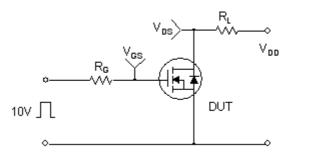


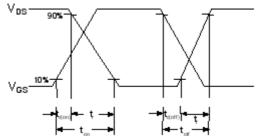


### **Gate Charge Test Circuit & Waveform**

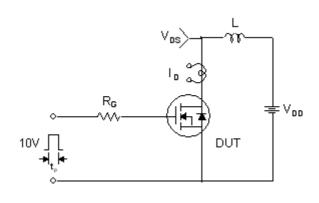


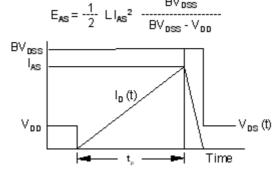
#### **Resistive Switching Test Circuit & Waveforms**



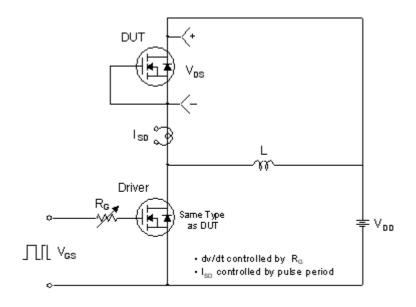


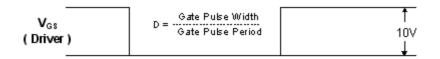
#### **Unclamped Inductive Switching Test Circuit & Waveforms**

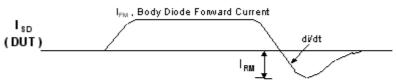




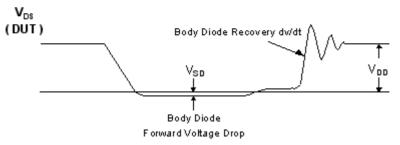
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms





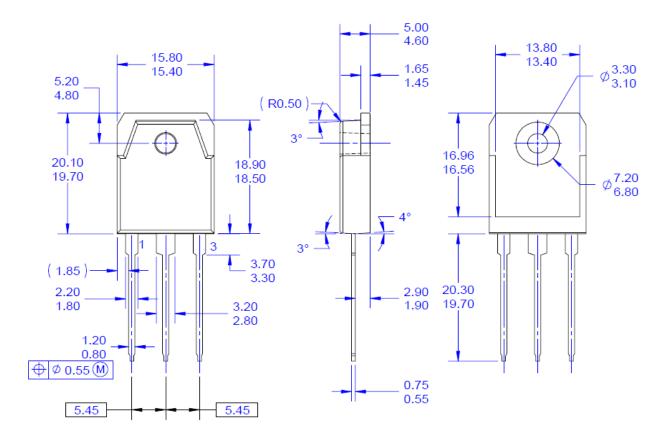


Body Diode Reverse Current



#### **Mechanical Dimensions**

# TO-3PN





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